Problem of the Peculiarities of Photo--Conductivity in Cadmium Selenide

BOV/56-34-3-3/55

at the argon point. The kinetics of the photo-conduction in the monocrystals of CdSe essentially depends on the properties of the exciting radiation, i.e. the parameters of the excitation- and damping processes of photocurrents are, otherwise conditions, functions of the wavelength & . A diagram shows, for example, the oscillographs of the photocurrent in the case of the excitation of the sample by a rectangular light impulse with two different values of  $\lambda$ , as well as by x-rays with a maximum hardness of 50 kV. Only the first of these cases corresponds to the linear problem, and the photcurrent J& depends exponentially on the time t. The second and third case show an essential deviation from the linearity in the initial stage of the increase of photocurrent. These initial stages correspond to a parabolic dependence of the photourrent, and this parabola then deforms to an exponential function. Here  $J_{\Phi} = \beta^* Lt$ , holds where L denotes the intensity of illumination, and  $\beta^*$  the quantum yield. Every deviation of this relation from the linearity is dependent on a dependence of the quantum yield on time. The excitation

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Problem of the Peculiarities of Photo--Conductivity in Cadmium

sov/56-34-3-3/55

with x-rays leads to an essential nonlinear problem. The scheme of transitions resulting from the experimental data found is shown in a diagram. This scheme is based on a two-stage excitation mechanism of photoconduction: The meaning of the single levels and transitions is shortly explained. There are 7 figures and 6 references, 3 of which are Soviet.

ASSOCIATION: Kiyevskiy politekhnicheskiy institut (Kiyev Polytechnical

Institute)

SUBMITTED:

May 22, 1957

Card 3/3

SYECHNIKOV, Sergey Vasil'yevich; GAVRILOVA, G., red.; SHAFETA, S., tekhn.red.

[Fundamentals of applied electronics] Osnovy tekhnicheskoi elektroniki. Kiev, Gos.izd-vo tekhn.lit-ry USSR. Pt.l.
[Power engineering electronics] Energeticheskais elektronika.
1959. 454 p. (MIRA 13:2)

(Power engineering) (Electronics)

中,这个人,我们是这个人,我们是这个人的人,我们就是这个人的人,我们就是这个人,我们也是这个人的,我们就是这一个人,我们是这个人的人,我们就是这个人的人,我们就

9.6150

S/194/62/000/008/016/100 D201/D308

AUTHOR:

Svechnikov, S.V.

TITLE:

Possibilities of using semiconductor photo-resistances

for the control of ionizing radiation

PERIODICAL:

Referativnyy zhurnal. Avtomatika i radioelektronika, no. 8,1962, abstract 8-2-106 f (In collection: Radioakt. metody kontrolya i regulir. proizv. protsessov, Riga, AS LatSSR, 1959, 279 - 293)

The following advantages of photo-resistances, used as indicators of ionizing radiation are considered: high sensitivity to radio-active and X-ray radiation also to the visible part of the spectrum, a high range of possible operating voltages and small dimensions. The most substantial disadvantage is the inertness of photo-resistances. Formulas, voltampere, dosimetry and spectral characteristics of semiconductor photo-resistances are given, together with oscillogramms of photo-currents, and temperature dependences. Formulas expressing the time constants of photo-currents are discussed. 9 figures. 18 references. [Abstracter's note: Complete Card 1/2

Possibilities of using	S/194/62/000/008/016/100 D201/D308	
translation.]		
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Card 2/2		

SOV/142-2-1-10/22 9(2)Evechnikov, S.V., and Petrenko, A.I. AUTHOR:

Cathode Followers (Slozhnyye katodnyye Composite TITLE:

povtoriteli)

Izvestiya vysshikh uchebnykh zavedeniy - radiotekh-PERIODICAL:

nika, 1959, Vol 2, Nr 1, pp 80-85 (USSR)

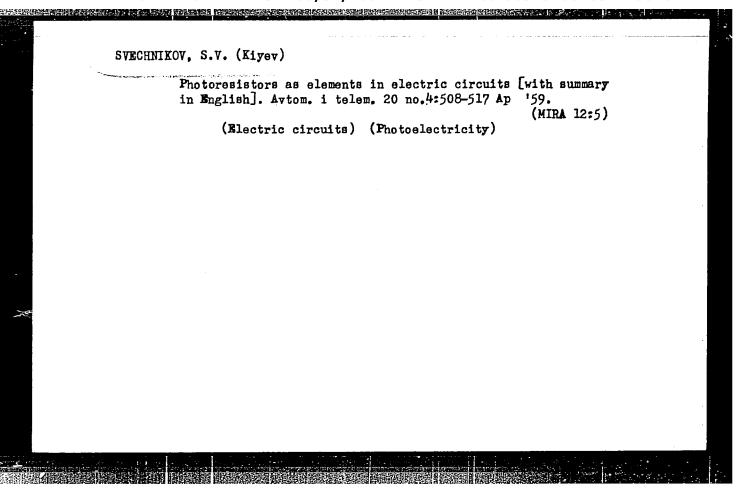
Cathode-loaded amplifier circuits, as shown in ABSTRACT: figure 1, found a wide-spread application in modern

electronic devices. High input resistances (107- $10^8$  ohms) at low output resistances  $(10^2-10^3)$  and a wide pass band (ranging from zero to some megacycles) require the application of cathode-loaded stages. The circuit, shown in figure 1, is not

ideal, since its transmission factor is smaller than 1 (0.8-0.9). Therefore, the authors investigate two multi-tube, cathode-loaded amplifier circuits, shown in figures 2 and 6, having an amplification factor close to 1. They explain a method for cal-culating such circuits for high input (lol ohms)

and low output (several tenths of an ohm) resist-Card 1/2

APPROVED FOR RELEASE: 08/31/2001 CIA-RDP86-00513R001654110010-2"



MORAVSKIY, Vladislav Eduardovich. Prinimali uchastiye: SVECHNIKOV, S.V., kand.tekhn.nauk; ROSSOSHINSKIY, A.A., kand.tekhn.nauk. TRET'IAKOV, F.Ye., kand.tekhn.nauk, retsenzent; LEYNACHUK, Ye.I., kand.tekhn.nauk, red.; ONISHCHENKO, N.P., red.

[Condenser discharge welding of small thickness metals] Kondensatornaia svarka metallov malykh tolshchin. Moskva, Gos.nauchnotekhn,izd-vo mashinostroit.lit-ry, 1960. 143 p.

(MIRA 13:7)

(Electric welding)

S/135/60/000/009/009/015 A006/A002

AUTHORS:

Moravskiy, V. E., Candidate of Technical Sciences, Khomenko, I. Z., Engineer, Svechnikov, S. V., Candidate of Technical Sciences

TITLE:

A Multi-Purpose Seam Capacitor WKM-3 (ShKM-3) Machine for Welding Thin Metal

PERIODICAL: Svarochnoye proizvodstvo, 1960, No. 9, pp. 28-30

TEXT: The authors developed and brought into use a seam capacitor ShKM-3 machine for welding 0.5 - 0.6 mm thick ferrous and non-ferrous metals. Engineers G. A. Belyakovich, S. I. Semergayev and A. G. Smagliy participated in the work. The main advantages of the machine are: a sufficiently accurate dosage of energy in welding the spots, producing resistant and tight seams, and the wide-range control of the welding conditions. This is obtained by synchronizing the control and the circuit voltage, required for an accurate consecutive charge and discharge of capacitance. The synchronization is obtained by the controlled operation of trigger valves forming with a stage the amplifier control system. Each trigger has two equilibrium states operated by triggering and cutting-off the valves. Disturbed syncronization affects the regular welding conditions.

Card 1/2

S/135/60/000/009/009/015 A006/A002

A Multi-Purpose Seam Capacitor WKM-3 (ShKM-3) Machine for Welding Thin Metal

A preliminary amplifying stage is connected to the circuit to raise the stability of the directing part of the system between the amplifier and the trigger cells. The extinction of the back current pulse in the initial coil of the welding transformer is performed by a shunting valva. Seam welding can be performed at a frequency of 50; 25; 12.5 and 6.25 cycles. The ShKM-3 machine permits the production of transverse and longitudinal seams. The transition from welding longitudinal to transverse seams is obtained by replacing the upper head and lower arm of the machine. The technical characteristics of the machine are given and its operation is described. Approximate welding conditions are given in a table. There are 1 table and 3 figures.

ASSOCIATION: Institut elektrotekhniki AN USSR (Institute of Electrical Engineering AS UkrSSR) Moravskiy, V. E. and Khomenko, I. Z.,
Kiyevskiy politekhnicheskiy institut (Kiyev Polytechnic
Institute) Svechnikov, S. V.

Card 2/2

MAYEVSKIY, O.A., dots., kand. tekhn. nauk; SVECHNIKOV, S.V., kand. tekhn. nauk, dots., otv. red.; TETEL'BAUM, Ya.I., kand. tekhn. nauk, dots., otv. red.; VYADRO, Sh.Ya., red.; MATVIICHUK, A.A., tekhn. red.

AND COMPANY TO THE RESIDENCE BEAUTION BATCHER FOR THE PROPERTY OF THE PROPERTY

[Electronics in technology and automatic control] Elektronika v tekhnologii i avtomatike. Kiev, 1961. 40 p. (Obshchestvo po rasprostraneniiu politicheskikh i nauchnykh znanii Ukrainskoi SSR, Ser.7, no.7) (MIRA 14:11)

(Automatic control) (Electronics)

PHASE I BOOK EXPLOITATION

CONTRACTOR OF THE PROPERTY OF

sov/5831

# Svechnikov, Sergey Vasil'yevich

Gazotrony i tiratrony; osnovy rascheta i konstruirovaniya (Gas-Filled Tube Rectifiers and Thyratrons; Design and Construction Principles) Kiyev, Gostekhizdat USSR, 1961. 323 p. 6300 copies printed.

Ed.: N. Polyanskaya; Tech. Ed.: S. Matusevich.

FURPOSE: This book is intended for designers and technologists concerned with gas-filled devices. It may also be useful to students of industrial electronics, electron vacuum and gas-filled devices, and gas discharge technique in schools of higher education.

COVERAGE: Operating principles and the fundamentals of the design and construction of gas-filled rectifiers and thyratrons are presented. The development of their design in accordance with the characteristics and parameters of a rectifier is discussed, and a series of practical examples given. The book is based on both Soviet and non-Soviet investigations. No personalities are mentioned. There are 115 references: 84 Soviet, 22 English 4 German, 2 French, and 3 Czech.

Card 1/7

S/142/61/004/003/001/016 E140/E435

: AUTHORS: Petrenko, A.I., Svechnikov, S.V.

TITLE: Basic directions in the development of reading

machines

PERIODICAL: Izvestiya vysshykh uchebnykh zavedeniy, Radiotekhnika,

1961, Vol.4, No.3, pp.239-253

TEXT: The article constitutes an extensive survey of Western literature on character recognition machines. The authors' main attention is given to English language sources. Two particular machines are discussed in detail, ERA (Solartron Electronic Reading Automaton) and FRED (magnetic-inc character reader of EMI Electronics Limited). The authors classify reading machines in three categories: 1. the use of mask-matching techniques; 2. the use of coded markers; 3. the detection of the semantic characteristics defining the character. It is stated that a great quantity of work is being carried on in this field in the USSR under the leadership of Corresponding Member of the Academy of Sciences A.A.Kharkevich, partially known to the Soviet reader. (Ref.1: Radiotekhnika, 1959, 14, No.5, 12; Ref.2: Radiotekhnika, Card 1/2

S/142/61/004/003/001/016 E140/E435

Basic directions in ...

1960, 15, No.2,3). Two further Soviet references which appear to concern concrete developments (Ref.53: Kovalevskiy, V.A. Semenovskiy A.G., Avtomatika i priborostroyeniye, Kiyev, 1960, No.1; Ref. 55: Saplin M.S., Elektronnyye vychislitel nyye mashiny, Mashgiz, 1960, 1) are not discussed in the article. V.S.Fayn is mentioned for his contribution in the field. There are 7 figures and 55 references: 5 Soviet and 50 non-Soviet. The four most recent English language references are as follows: Young D.A., Electronic Engineering, 1960, 32. January; Wada H., Takahashi S., Iijima T., Imoto K., UNESCO (NS) ICIP June, 1960, No.6; The FRED Character Reader and Associated Equipment for Banking, EMI Electronics, 1960; Direct Reading for Data Processing, Electronic Engineering, 1960, February, 95.

ASSOCIATION:

Kafedra promyshlennoy elektroniki Kiyevskogo ordena Lenina politekhnicheskogo instituta (Department of Industrial Electronics, Kiyev Order Lenin Polytechnical Institute)

SUBMITTED: Card 2/2

November 4, 1960

SVECHNIKOV, S.V.; PETRENKO, A.I.

Matching stages with low output impedance. Izv. vys. ucheb. zav.; radiotekh. 4 no.5:620-623 '61. (MIRA 14:12)

1. Rekomendovano kafedroy promyshlennoy elektroniki Kiyevskogo ordena lenina politekhnicheskogo instituta.

(Electric networks)

(Cathode followers)

SVECHNIKON, S.V.

28438

\$/185/61/006/002/010/020

D210/D304

26.2421

AUTHORS: Konozenko, I.D., Svyechnykov, S.V., and Chala, V.H.

TITLE:

Some features of photo and X-ray - conductivity of

single crystals of cadmium sulphide

PERIODICAL: Ukrayins'kyy fizychnyy zhurnal, v. 6, no. 2, 1961,

207 - 212

TEXT: In this article the authors describe measuring current relaxation of single crystals of cadmium sulphide induced by visible light and X-rays, giving a qualitative explanation on the similarity of these two phenomena. This work as done because despite the large amount of data on X-ray conductivity, no adequate theory exists which would allow the prediction of conductivity induced by visible light. The best comparison of the effect of X-rays and light on electrical conductivity can be made at the beginning of the curve I = f(t), where essentially electron attachments are controlling. Assuming at the same time that within certain limits

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28438 S/185/61/006/002/010/020 D210/D304

Some features of photo and ...

the mean life of current carriers is independent of the mode of excitation, then the current decay curves should be of the same type for X-rays and for visible light. A suitable basis for comparison then is to work under conditions of equal absorption coefficient and equal power absorption by the lattice. The authors have, therefore, made measurements under conditions of equal absorption coefficients for the X-rays and visible light, and equal stationary currents through the crystal, as the power absorption could not be measured directly. The cadmium sulphide crystals were grown from vapor phase, by a method developed at the Institute. Aluminum electrodes were used. These gave linear characteristics from a fraction of a volt to a few line hs volts. The X-ray machine gave a supply of steady intensity from which the copper line k, was separated giving an absorption coefficient of 103 cm-1 in CdS. A corresponding coefficient for visible light is obtained at  $\lambda = 5100$  Å. The monc - matic light was obtained using interference filters giving transmission bands of  $\Delta\lambda=80$  %. The experimental arrange-

Card 2/4

**电阻性检查性 医眼中的经过滤器 40.** 

28438 S/185/61/006/002/010/020 D210/D304

Some features of photo and ...

ment allowed separate or simultaneous excitation with continuous or pulsed signals of the necessary (sufficiently long) duration. The commencement and removal of excitation was registered by a germinium photodiode. The CdS current and the photodiode current were simultaneously recorded on a loop oscillograph. Conductivity measurements made on samples kept in darkness for one hour showed little change from ordinary samples for X-rays, but a fairly large change was observed for visible rays due to the equilibrium relationship between electrons and corresponding levels in the forbidden zone. Similar effects were obtained for extra illumination. For illumination with white light, to give a current of  $0.6 \times 10^{-7}$  amp. the S shape and the point of inflection were removed in most cases, resulting in similar curves for X-rays and visible light. There are 4 figures and 15 references: 5 Soviet-bloc and 10 non-Sovietbloc. The references to the 4 most recent English-language publications read as follows: Hollander, Nucleonics, 14, b, 10, 1956; Sihvonen, Rev. Scient. Instr., 27, b, 5, 1956; Frederichs Jacobs., Gen. El. Rev., 54, b, 1, 1956; Dutton, Phys. Rev., 112, b. 3, 1958.

Card 3/4

28438 S/185/61/006/002/010/020 D210/D304

Some features of photo and ...

ASSOCIATION: Instytut fizyky AN URSR m. Kyyiv (Institute of Physics, AS UkrSSR, Kiyev)

June 30, 1960 SUBMITTED:

Card 4/4

S/143/61/000/012/003/005 D299/D305

9,4310 (1003,1143,1150)

AUTHORS:

Svechnikov, S.V., Candidate of Technical Sciences,

Docent, and Kalnibolotskiy, Yu.M., Engineer

TITLE:

Test circuits for powerful semiconductor valves

PERIODICAL:

Izvestiya vysshikh uchebnykh zavedeniy. Energetika,

no. 12, 1961, 45 - 50

TEXT: A testing device is described for the study of semiconductor rectifiers. In order to ensure reliable operation of the rectifiers, it is necessary to protect the semiconductor valves from overload currents, so that the temperature of the p-n junction should not exceed the maximum permissible. Hence the importance of determining the overload capacity of germanium- and silicon valves. Experimental determination of the overload characteristics is based on measurements of the mean temperature inside the valve. The temperature of the p-n junction can be measured by a thermocouple or by using the dependence of the reverse current of the valve on the temperature of the p-n junction. The first method is less accurate Card 1/4

33331 S/143/61/000/012/003/005 D299/D305

Test circuits for powerful ...

than the second. The test circuits (i.e. the circuits used for determining the overload characteristics) described below, are based on the second method. The simplest test circuit involves measurement of the direct and reverse current of the diode under investigation, whereby both currents flow through a single loop. This is inconvenient, as the slow surface-states involved may distort the results. A circuit with separate loops for the direct- and reverse current, is free of this shortcoming; the loops are divided by means of a synchronous switch. This circuit, too, is defficient, owing to the presence of the mechanical switch. The above shortcomings were eliminated by means of a circuit, developed by the authors, in which the synchronous switch has been replaced by a controlled current-generator. Fig. 4 shows a diagram of the circuit. Transformer T and ignitron I generate the direct-current pulses. The control device C provides for the appropriate moment of ignition of the ignitron.  $D_1$  is the tested diode. The ratio of the mean surrents through the ignitron and the semiconductor is of the order of  $10^3 - 10^4$ . A block diagram of the testing device shows its other components: A rectangular-pulse formation unit, time re-Card 2/4

33331 S/143/61/000/012/003/005 D299/D305

Test circuits for powerful ...

rely, comparator and pulse counter. The testing device can be used for study of thermal processes in powerful germanium- and silicon valves, under any external conditions. It can be also used for designing valves of a pre-assigned overload capacity. The time dependence of the temperatures of the p-n junctions, obtained by means of the device, can be used for designing an equivalent thermal transient process; by investigating this process it is possible to determine the optimum valve characteristics for given requirements. As an illustration, the time dependence of the p-n junction temperature is plotted, and the equivalent electrical circuit is shown. In conclusion, the testing device described, permits studying the thermal characteristics of germanium— and silicon diodes which, in turn, makes it possible to ensure adequate reliability of rectification. ers, while taking greatest advantage of the properties of semiconductor tubes. There are 6 figures and 5 references: 2 Soviet-bloc and 3 non-Soviet-bloc (in translation).

ASSOCIATION:

Kiyevskiy ordena Lenina politekhnicheskiy institut (Kiyev Order of Lenin Polytechnic Institute)

Card 3/4

33331 S/143/61/000/012/003/005 D299/D305

Test circuits for powerful ...

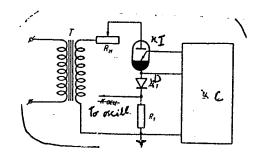
PRESENTED:

by Kafedra promelektroniki (Department of Industrial Electronics)

SUBMITTED:

May 11, 1961

Fig. 4.



Card 4/4

ACCESSION NR: AT3004539

\$/2947/62/002/000/0153/0160

AUTHOR: Svechnikov, S. V.; Chalaya, V. G.

TITLE: Spectral distribution of the internal photoelectric effect in single crystals of cadmium sulfide during excitation by x-rays

SOURCE: Radioizotopny\*ye metody\* avtomaticheskogo kontrolya; trudy\* rasshirennogo soveshchaniya Vsesoyuznogo seminara po primeneniyu radioaktivny\*kh izotopov v izmeritel'noy tekhnike i priborostroyenii, v. 2, Frunze, 1962, 153-160

TOPIC TAGS: spectral distribution, photoelectric effect, crystal, Cd, S, current carrier, Cr, Fe, Co, Mo, Cu, Ag, W, monochromatic light, visible light, wave length, sensitivity, energy, impurity, injection, excitation, quantum yield, hard radiation, soft radiation

ABSTRACT: The considerable conductivity of CdS in x-rays is manifest in a wide range of wave lengths and depends on the hardness of the radiation, the size and properties of the crystal itself, and, especially, the quantity and quality of the injected impurities. Experience has shown that crystals of CdS that are sensitive to x-rays have energies of 0.5-1.5 Mev. The authors detected no correlation between sensitivity of CdS single crystals to visible light and sensitivity of crys-Cord 1/3

ACCESSION NR: AT3004539

tals to x-rays. Spectral curves were made for crystals 5, 19, 34, and 300 microns thick. Tubes were used as a source of monochromatic radiation, the tubes having an anticathode of Cr, Fe, Co, Mo, Cu, Ag, or W. Ko radiation was used with a crystal monochromator, permitting a range of wave lengths from 0.2 to 2.3 Å. It was found from the experiment that the results depend essentially on the coherence of the monochromatized radiation. The spectral distribution of the additional current in single crystals during excitation by x-rays was found to depend on several factors. The current was found to increase with hardness of the radiation, in correspondence with increase in quantum yield. The principal maximum of the curve i = f( $\lambda$ ) lies in the short-wave part of the spectrum, in the region of  $\lambda$ <0.71 Å. Its position is determined by the reabsorption of secondary radiation of Cd and is a function of crystal thickness: with increase in crystal thickness the maximum of the additional current shifts toward shorter wave lengths. The curves of spectral distribution of the additional current obtained under conditions of constant absorption of quanta in the crystal are similar to those obtained under conditions of constant absorption of energy. This leads to the conclusion that the average lifetime of current carriers in single crystals of CdS does not depend, in the first approximation, on wave length of the x-rays in the range  $\lambda$  = 2.3 - 0.71 Å. The deltaform shape of the curve i = f( $\lambda$ ) is reason for stating that single crystals of CdS may be used as selective receivers of x-rays of low and medium Card 2/3

EDM	COMMENSACION PRODUCTION OF THE PROPERTY OF THE	
	ACCESSION NR: AT3004539	
·	hardness. Orig. art. has: 3 figures,	1 table, and 11 formulas.
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	Card 3/3	

Cvervoltages in germanium rectifiers during switching operations.

Izv. vys. ucheb.; radiotekh. 5 no.1:66-76 Ja-F '62. (MIRA 15:5)

1. Rekomendovana kafedroy promyshlenncy elektroniki
Kiyevskogo ordena Lenina politekhnicheskogo instituta.

(Electric current rectifiers)

(Germanium diodes)

2005年2001年18日1日 1907年 19 s/185/62/007/004/010/018 SVECHNIKOV D407/D301 Svyechnykov, S. V., Chalaya, V. H., and li di On the probe characteristics of X-ray and 24.3500 Sheynkman, M. K. photoelectric current in CdS-type single AUTHORS: Ukrayins'kyy fizychnyy zhurnal, v. 7, no. 4, crystals TITLE: The dependence was studied of the photocurrent on the The dependence was studied of the photocurrent on the exciposition of the probe (between the electrodes) during the exciposition of the probe (ds. case. gingle crystals by a narrow tation of das case. Case. position of the prope (petween the electrodes) during the excipation of the prope (between the electrodes) during the excipation of the property of the following processes tation of CdS, CdSe, CdS x influence of the following processes PERIODICAL: light or X-ray probe. The influence of the following processes on the conductivity of the single crystals under local excitation was considered: electron drift from the lighted to the dark tion was considered. on the conductivity of the single crystals under local excitation was considered: electron drift from the lighted to the dark tion was considered; bipolar diffusion of photocarriers, exciton side of the crystal, bipolar diffusion of photocarriers. Card 1/3

S/185/62/007/004/010/018 D407/D301

On the probe...

diffusion, resonance energy transfer in dipole-dipole interactions, reabsorption of the luminescence light, etc. It was found that no definite conclusion can be reached for the dominant photo-current component and the role of the hole component by considering the stationary probe characteristic of the photo-current only. The probes were 0.1 mm thick, which is by one order of magnitude less than the distance between the electrodes. Visible light of various wavelength was used; the wavelength of the X-rays was 0.708 and 2.285 Å. It was found that the maximum of the probe characteristic can be located (for both the light and the X-rays) at the cathode, anode, and also between them. The value of the photocurrent at the maximum of the probe characteristic near the cathode is about 10<sup>-6</sup> - 10<sup>-8</sup> amp. This is about 4 - 5 orders of magnitude higher than the calculated values. The trapping factor q was estimated (q = 10<sup>3</sup>). The photocurrent at the anode was also larger than predicted by theory. The

Card 2/3

SUECHNIKOV, S.V.

38843

94177

S/185/62/007/006/006/014 D407/D301

AUTHORS:

Svyechnikov, S. V. and Chalaya, V. H.

TITLE:

Peculiarities of the longitudinal photoconductivity of

CdS-type single crystals

PERIODICAL:

Ukrayins'kyy fizychnyy zhurnal, v. 7, no. 6, 1962,

623-628

TEXT: The current-voltage and lux-ampere characteristics of the longitudinal photoconductivity of CdS and CdSe single-crystals were investigated, various contacts being used. The contacts were applied to the crystal either by cathode pulverization or by vacuum sublimation. Cd and In were used as ohmic contacts, whereas Ag, Au and Cu were used as non-ohmic contacts. The latter had a filtering effect, causing a shift in the photocurrent maximum towards the longwave side of the spectrum. It was found that CdS single-crystals with filtering contacts are sensitive in a very narrow spectral region, for which the absorption coefficient of CdS is relatively small (less than 10 cm - 1). The peculiarities of the CdS-Card 1/3

S/185/62/007/006/006/014 D407/D301

Peculiarities of the...

type single crystals can be summed up as follows: 1) A strong dependence of the current-voltage and lux-ampere characteristics on the material of the contact and on the method of its application. 2) Over-linearity of the dark current-voltage characteristics, with a slope exceeding 2; these characteristics become linear by illumination (in the specimens with Ag and Au contacts); this is due to the different dependence of the space charge and of the photocurrent on the voltage; the coefficient of photorectification attains values of up to 10<sup>4</sup> - 10<sup>5</sup>. 3) The appearance in the current-voltage characteristics of a strongly pronounced hysteresis, with a relaxation time of tens of seconds; this is due to the formation of a space charge in the crystal and the contacts. 4) Quasi-saturation of the lux-ampere characteristics, whose slope varies from 0.04 - 0.06 at low voltages to 0.2 - 0.3 at high ones (with illumination exceeding 100 lux). The quasi-saturation effect is related to the presence of high-resistance sections in the crystal. 5) The appearance of a photovoltage of the order of 200 - 250 millivolt in specimens with Cu-Cd contacts; this can be ex-

Card 2/3

Peculiarities of the ...

S/185/62/007/006/006/014 D407/D301

plained by the presence of a high gradient of carrier concentration in the bulk of the crystal, arising as a result of a sharp weakening in illumination. The properties of the longitudinal photoconductivity of CdS single crystals can be used for development of efficient and compact photoresistors of very low voltage, suitable to operate as keys. There are 4 figures.

ASSOCIATION: Instytut fizyky AN UkrRSR, Kyyiv (Institute of Phy-

sics of the AS UkrRSR, Kiyev)

SUBMITTED: January 23, 1962

Card 3/3

SVECHNIKOV, Sergey Vasil'yevich, kand. tekhn.nauk; PETRENKO, A.I., kand. tekhn. nauk, retsenzent; DEREVETS, S.K., red.izd-va; STARODUB, T.A., tekhn. red.

[Principles of technical electronics] Osnovy tekhnicheskoi elektroniki. Kiev, Gostekhizdat USSR. Pt.2. [Amplifier and generator circuits] Usilitel'nye i generatornye tsepi. 1963. 480 p. (MIRA 17:1)

(Electronic circuits)

SVECHNIKOV, S.V.; CHALAYA, V.G.

Photoresistors under key conditions. Avtom. i prib. no.2:62-64 Ap-Je '63. (MHA 18:8)

1. Institut poluprovodnikov AN UkrSSR.

Contactless photopotentiometer. Avtom. i telem. 24 no.9:
1292-1294 S '63. (MIRA 16:9)
(Potentiometer) (Photoelectric cells)

EWP(q)/EWI(m)/BDS AFFTC 18252-63 ACCESSION NR: AP3002120 AUTHOR: Chalaya V. G., Svechny\*kov S. V. TITLE: On the equivalent circuit and photocapacitance of longitudinal CdSphotoresistors SOURCE: Ukrains kyy fizychnyy zhurnal, v. 8, no. 6, 1963, 664-668 TOPIC TAGS: nonlinear contact, longitudinal photoresistance, capacitance, illumination, barrier layer, leakage current, CdS, CdS photoresistor CdS detector, equivalent circuit. ABSTRACT: The capacitance of longitudinal CdS photorsistors with non-linear contacts is of considerable magnitude. It depends on voltage applied to the sample and its illumination. Its nature is associated with the presence in the contacts of sections with high resistivity and characteristic dimensions of about 10-6cm. The dependence C = f'(L) between the capacitance and illumination was studied. The range of illumination varied from zero to several hundred lux. Within these limits the relationship was linear to first approximation. The authors developed the equivalent circuit of a longitudinal photoresistance. The method of measurements and the actual circuit used are described. The capacitance and leakage Card 1/2

L 18252-6;				
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equations.	lts it is 104_	e taken into account. The sver one volt is 10 <sup>2</sup> pf/lux, 10 <sup>5</sup> pf/lux. Orig. art. has	and at voltages of the or s 5 figures and 4 numbers	rder
ASSOCIATIO	(Institute	Napivprovidny*kiv AN URSR, K of Semiconductors of UkrSSR	Acad. Sci.)	<b>y</b>
SOBULTIND:	21 Nov 62	DATE ACQ: 12 Jul 63	ENCL: 00	
SUB CODE:	РН	NO REF SOV: 000	OTHER: OOL	

SVECHNIKOV, S.V. [Swiechnykov, S.V.]; CHALAYA, V.G. [Chalaia, V.H.]

Spectral distribution of the X-ray conductivity of CdS single crystals. Ukr. fiz. zhur. 8 no.10:1157-1163 0 '63.

Problem of ohmic contacts to photovaristors from CdS single crystals and its analogs. Ibid.:1164-1169 (MIRA 17:1)

1. Institut poluprovodnikov AN UkrSSR, Kiyev.

TETEL'EAUM, Yakov Isaakovich, kand. tekhn. nauk [deceased];
SVECHNIKCV, S.V., kand. tekhn.nauk, retsenzent

[Semiconductor rectifiers] Napivprovidnykovi vypriamliachi. Kyiv, Tekhnika, 1964. 257 p. (MIRA 17:8)

ACCESSION NR: AP4040429

5/0302/64/000/002/0058/0059

AUTHOR: Oleksenko, P. F.; Svechnikov, S. V. (Candidate of technical sciences)

TITLE: Preamplifying correcting stage for photovaristors

SOURCE: Avtomatika i priborostroyeniye, no. 2, 1964, 58-59

TOPIC TAGS: photovaristor, FSK-M photovaristor, preamplifier, correcting preamplifier, correcting preamplifier photovaristor

ABSTRACT: Two quadripoles intended for correcting the inertia of a photovaristor are discussed. The first consists of two resistors and one capacitor (see Fig 3b, Enclosure 1), and the second includes a 2-tube positive-feedback preamplifier (Fig 3c) which acts as a negative resistance. Simplified connection diagrams, data, and oscillograms are given in Enclosure 1 for a Soviet-made FSK-M photovaristor. Orig. art. has: 3 figures and 3 formulas.

ASSOCIATION: Institut poluprovodnikov AN UkrSSR (Institute of Semiconductors,

AN UkrSSR)

SUBMITTED: 00

SUB CODE: EC

DATE ACQ: 24Jun64

NO REF SOV: 002

ENCL: 01

OTHER: 000

Card 1/2

DENBNOVETSKIY, S.V.; SVECHNIKOV, S.V.

Methodology of studying the parameters of relaxation processes in physical systems. Prib. i tekh. eksp. 9 no.1:110-114 Ja-F '64. (MIRA 17:4)

1. Institut poluprovodnikov AN UkrSSR.

ACCESSION NR: AP5001744 S/0302/64/000/004/0051/0054

AUTHOR: Syechnikov, S. V. (Candidate of technical sciences): Shuvagev. V. A.

TITLE: Voltage-function photoconverter

SOURCE: Avtomatika i priborostroyeniye, no. 4, 1964, 51-54

TOFIC TAGS: photoconverter, voltage function converter

ABSTRACT: An analog-to-analog photoconverter is proposed as a substitute for mechanical sliding-contact potentioneters. The converter consists of a transistor with the input voltage applied between its emitter and base and a gasfilled cold-cathode lamp connected into its collector circuit. As the lamp luminescence intensity is proportional to its current in a wide range, a (selenium-cadmium) photovaristor placed near the lamp will pass a current proportional to the input voltage. Temperature stabilizing resistors are provided in the circuit. The inertia of both the lamp and photovaristor is responsible for a Cord 1/2

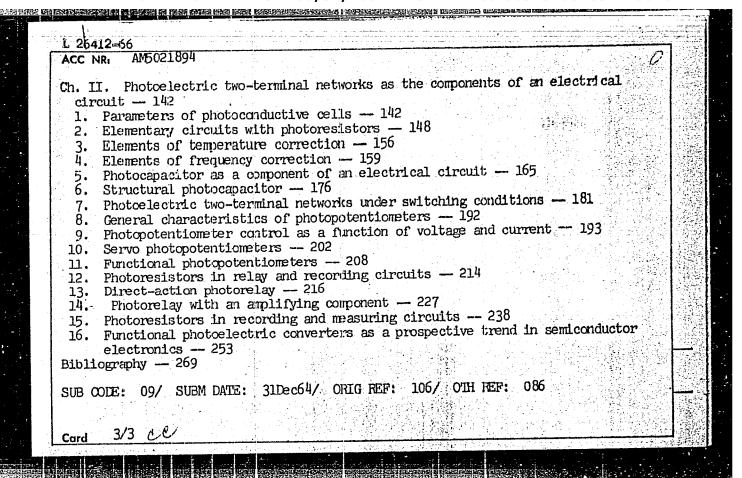
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ACCESSION NR: AP5			
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SUBMITTED: 00		ENGL: 00	
SUB CODE: F.C	NO REF SOV: 001	. OTHER: 001	
		J. Carper	

KROLEVETS', Konstantin Mikhaylovich, inzh.; SVECHNIKOV, S.V.,
kand. tekhn. nauk, retsenzent

[Position-sensitive photocells] Slidkuiuchi fotoelementy.
Kyiv, Tekhnika, 1965. 139 p. (MIRA 18:9)

L 26412-66 EW ACC NR. AM5021	894	Monograph		UR7 5-8
Svechnikov, Sem	ey Vasil'vevich (D	Octor of Technical Sci	lences)	8+1
Photoelectric tw 1965. 279 p.	o-terminal network illus., biblio. 30	s (Fotodvukhpolyusnik 100 copies printed	1) Kiev, Izd-vo "Tek	
TOPIC TAGS: phonetwork, semic	otoelectric cell, p conductor research,	photoconductivity, photoconducti	tœlectric effect, e	lectric
the development also be useful Physical print works as prospend conversion ditions of physical print takes are	t and utilization to advanced stude ciples of the analy pective components in are presented.	Is intended for scient:  n of photoelectric sements in schools of highests and design of phofor automation, contribe parameters, characocapacitors, photopote respects of using a phong are discussed.	her technical educat toelectric two-termi ol, measurement, reg teristics, and opera	tion. inal net- gulation, ating con- toelectric
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1 .	4. Photoelectric two-terminal recording as
	conversion system — 24  5. Spectral characteristics — 29  6. Spectral characteristics — 29
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	7. Lux-ampère diaracteristics — 55 8. Volt-ampère characteristics — 55
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	2. Transient characteristics of photoelectric two-terminal networks — 93  3. Stabilizing processes in A <sub>2</sub> B <sub>6</sub> -type photoelectric two-terminal networks — 93  3. Stabilizing processes in A <sub>2</sub> B <sub>6</sub> -type photoelectric two-terminal networks — 93
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	the determination of their parameters — 133
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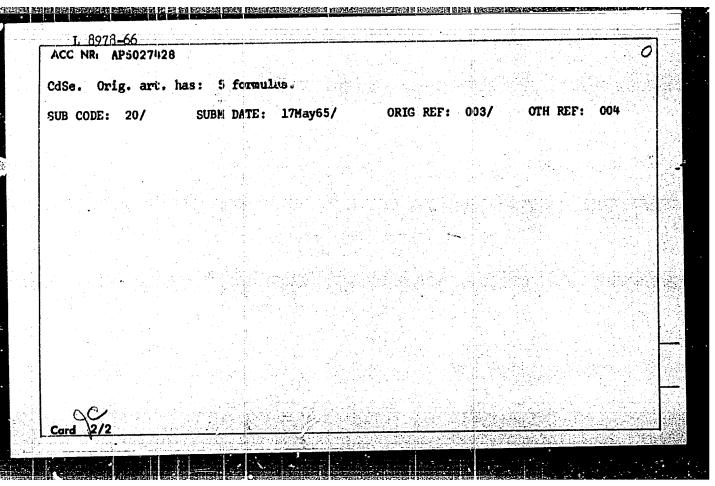
#### "APPROVED FOR RELEASE: 08/31/2001

#### CIA-RDP86-00513R001654110010-2

BB/GG L 4495-66 EWT(d)/EWP(v)/EWP(k)/EWP(h)/EWP(1) IJP(c) UR/0302/65/000/003/0026/0027 ACC NR: AP5023269 621.142.353.3 Svechnikov, S. V. (Candidate of technical Oleksenko, P.F AUTHOR: Krasnikov, N.I. sciences) TITLE: High-speed division analog computer SOURCE: Avtomatika i proborostroyeniye, no. 3, 1965, 26-27 TOPIC TAGS: analog computer, computer circuit, computer design, automatic control system, semiconductor device ABSTRACT: This article describes a high-speed analog device for the division of unipolar pulses of arbitrary spectral shape (0-105 cps) with a dynamic range of 300 and 50 with respect to the divisor and dividend. The circuit was designed at Institut poluprovodnikov AN UkrSSR (Institute of Semiconductors, AN UkrSSR) The circuit diagram is presented, and static and dynamic characteristics are given, as well as the theoretical description of the device. The device may be widely used in automatic control systems and in the field of computing. Orig. art. has: 4 formulas and 3 figures. ASSOCIATION: none SUB CODE: IE, DP, EC ENCL: 00 SUBMITTED: 00. OTHER: 002 NO REF SOV: 001

1. 8978-66 ENT(1)	/EWT(m)/T/EWP(t)/EWP(b)/EWA(c) LIP	/0181/65/007/011/3413/3415
ACC NRI AP5027428	SOURCE CODE: OF	6
AUTHOR: Svechnikov	, S. V.; Chalaya, V. G.	
ORG: Institute of	4,55 Semiconductors AN UkrSSR, Kiev (Insti	tut poluprovodníkov AN UkrSS
TITLE: Determining	the energy of an electron-hole pair	and absolute quantum yield
for radioconductivi	ty in CdS and CdSe single crysta's	
SOURCE: Fizika tve	rdogo tela, v. 7, no. 11, 1965, 3413-	3415
•	m sulfide, cadmium selenide, quantum	<b>L</b>
ABSTRACT: Single	rystals of CdS are exposed to monochi	omatic Cu-K radiation and
thole pair are meas quantum yield of () separation energy ( ± 0.02)·10 <sup>3</sup> electro	eld of radioconductivity and energy ured. Data from measurements on this 1.8 ± 0.06)·10 <sup>3</sup> electrons per absorbed (4.96 ± 0.17) ev. Similar measurements per absorbed quantum and (4.22 ± 0.05)	quantum, and an average painents for CdSe gave (2.1 *
satisfactorily with	the empirical formula	
	$\varepsilon = (E_q + 2.5) \text{ ev}$	
where $E_a$ is the wid	ith of the forbidden band, giving $\varepsilon =$	4.9 ev for CdS and 4.2 ev for
, <b>v</b>		

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L.64746-65 EWT(1)/1/EWA(h)	YUP(c) AT(s)	
ACCESSION NR: AP501543	4 UR/0185/65/010/005/0597/0600	
AUTPORS: Svyechnykov, (Chalaya, V.G.)	W/SS.V. (Svechnikov, S.V.); Chalaya, V. H.	
TITLE) Investigation o x-ray conductivity of S y V/V	the phenomenological quantum yiels of the	
SOURCE: Ukráyins Lyy f	Leychnyy zhurnal, v. 10, no. 6, 1965, 597-600	
TOPIC TAGS: cadmium su	lide, x ray, conductivity, photoconductivity,	
quantum yield, radiativ		
ABSTRACT: The quantum	eld of the x-ray conductivilty and its de-	
pendence on various par was determined from the	meters is investigated. The quantum yield honorocurrent increase following pulsed ex-	
citation. The current	increase was measured with the aid of measur-	
The x-ray source was th	monochromatized Ko radiation of a copper	
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L 64746-65 ACCESSION NR: AP5015434

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x-ray tube supplied with rectified, smoothed, and stabilized voltage. The width of the x-ray beam in the plane of the sample was about 0.2 mm. This was also the distance between the electrodes. The number of quanta incident on the sample was determined with an MSTR-5 counter of known efficiency and an RE-1 scaler. The number of quanta absorbed by the crystal was found from its known thickness. The phenomenological photoconductivity quantum yield was measured by the usual method. The sample was illuminated for the same amount of time as with x-rays. The current increase was measured similarly, and the optical wavelength chosen (5100 Å) was close to the photosensitivity maximum of CdS and such that the absorption coefficient was equal to that of 1.54-A x-rays. On increasing the illumination with visible light the quantum yield of the photocurrent decreases, indicating the simultaneous presence of slow trapping t-levels and s-channel recombination. The quantum yield curve as a function of the x-ray illumination is qualitatively similar. Good correspondence between the light and x-ray yields is also observed in the case of a sample

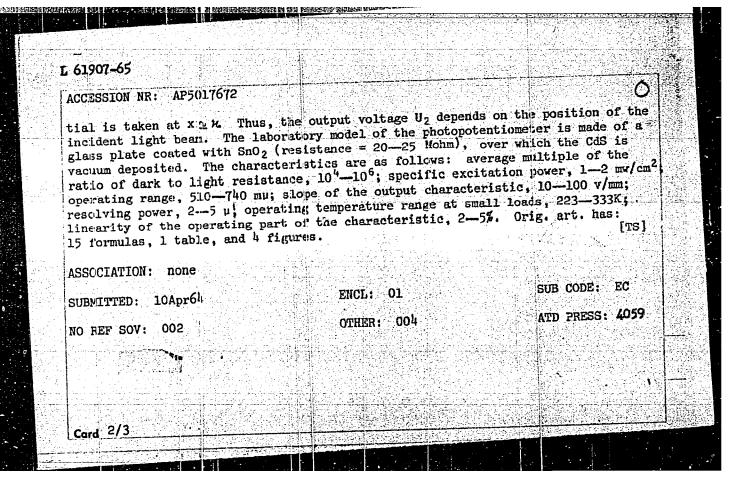
. 64746-65 ACCESSION NR: AP5015434	Control of the contro		3	
n which recombination s- lition to r-levels. The 0.30. The absolute value ogical quantum yield are	maximum yield at opt s of the measured lic presented. It is co	imal illumina ght and x-ray oncluded that	ation is y phenomeno- t a correla	
cion exists between the poretical results for the mas: 3 figures and 1 tables association: Enstitut na	former applicable to Le. apivprovidnykiv AN UR	the latter. SR (Institut	Orig. art	
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IIP(c) EEC(b)-2/EWA(h)/EWI(1) Pz-6/Peb L 63649-65 UR/0109/65/010/007/1310/1313 ACCESSION NR: AP5017668 621.383.44.01 20 AUTHOR: Krolevets, R. M.; Sveclinikov, S. V. TITLE: Relaxation of photoresponse of "Isteral" photocells 75 SOURCE: Radiotekhnika i elektronika, v. 10, no. 7, 1965, 1310-1313 TOPIC TAGS: photocell, photodiode, germanium photocell, silicon photocell ABSTRACT: The results are reported of an experimental investigation of the photo-response relaxation in Ge and Si "lateral" photocells. The photocells were illumi-nated by light pulses from a 1-mm slit, had a duration of a few dozen used and a pulse rise (or fall) time of 2-2.5 usec, and their repetition rate was 50 cps. The illumination of the photocell surface was adjustable from zero to a few thousand lux. Ge photocells were tested at 293 and 264K; Si photocells, at 293 and 400K. It was found that the "lateral" photoresponse relaxation is determined by the proc-esses of relaxation of a losded photovoltaic cell (which are well known) and by the processes of charging (and discharging) the capacitance of the nonilluminated part of the p-n junction through the "lateral" resistance of the upper layer. Oscillograms of the photoresponses of Ge and Si photocells at the above temperatures are shown. Orig. art. has: 2 figures. Card 1/2

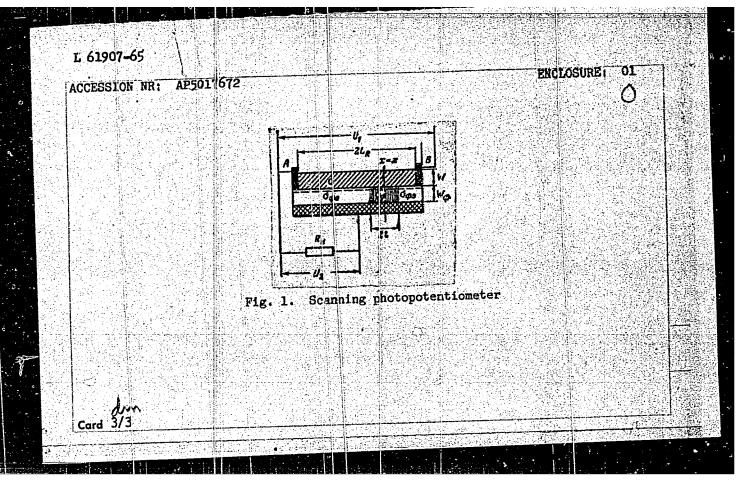
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3619-65 ACCESSION NR: AP5017668			
ASSOCIATION: none SUMMITTED: 24Apr64 NO REF SOV: 005	ENCL: 00	SUB CODE: EM, SS ATD PRESS: 4055	
Card 2/2			

L 61907-65 ACCESSION NR: APSO17672 UR/0109/65/010/007/1335/1340 621.383.42:546.48 22 AUTHOR: Zyugenov, A. N.; Svechnikov, S. V. TITLE: Contactless scanning photopotentiometer SOURCE: Radiotekhnika i elektronika, v. 10, no. 7, 1965, 1335-1340 TOPIC TAGS: photopotentiometer, servo photopotentiometer, cadmium sulfide photopotentiometer ABSTRACT: The construction, principle of operation, and characteristics of a Cd3-base contactless photopotentiometer are examined. As shown in Fig. 1 of Enclosure, the photopotentiometer includes resistive layer o, where a potential drop U is formed from an external current source, and photoconductor  $\sigma_{\phi 0}$  which contacts the resistive layer o along its entire length. The second contact of the photoconductor serves as the collector (K). The load is connected between one of the input clamps (A and B) and the collector. When a narrow light beam of width 26 strikes the conductor, a conducting bridge forms between o and K. Since the resistance of the bridge is somewhat lower than that of the dark area of the conductor, the current thus produced is bounded by the beam width. The reading of the poten-Card 1/3



"APPROVED FOR RELEASE: 08/31/2001 CIA-RDP86-00513R001654110010-2



L 17596-66 EWA(h)/EWT(1)
ACC NR: AP6000570 SOUR

SOURCE CODE: UR/0109/65/010/012/2264/2266

AUTHOR: Zyuganov, A. N.; Svechnikov, S. V.

22

ORG: none

TITLE: Photocapacitor based on cadmium sulfide

SOURCE: Radiotekhnika i elektronika, v. 10, no. 12, 1965, 2264-2266

TOPIC TAGS: photocapacitor, CdS photocapacitor

ABSTRACT: Experimental characteristics of the CdS photocapacitor which was initially developed by F. Gordon et al. (IRE Convent. Rec., 1957, 5, 3, 40) are presented and discussed. The characteristics show that the capacitance of this device varies by 150-300% when the luminous intensity varies by 3 orders of magnitude. The properties of the photocapacitor are characterized by its "reduced transconductance" whose curve has a pronounced maximum. The maximum transconductance point of the photocapacitor should be used only in medium-frequency RC-circuits. At high frequencies, the transconductance is very low. A considerable inertia (0.1 sec) is held as a serious disadvantage of the CdS photocapacitor. Orig. art. has: 4 figures and 9 formulas.

SUB CODE: 09 / SUBM DATE: 24Oct64 / ORIG REF: 000 / OTH REF: 001

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UDC: 621.383.9:621.382.28

L 06390-67 EWT(:n)/EWP(t)/ETI LJP(c) JD SOURCE CODE: UR/0103/66/060/003/0142/0147	
1 ACC NP. 496010289	
AUTHOR: Zyuganov, A. N. (Kiev); Oleksenko, P. F. (Kiev); Svechnikov, S. V. (Kiev)	
ORG: none TITLE: The effect of load resistance upon the transient characteristics of photoresistances	
SOURCE: Avtomatika i telemekhanika, no. 3, 1966, 142-147	•
TOPIC TAGS: photoresistance, photoconductive cell, electronic feedback, cadmium sele- nide, cadmium sulfide  ABSTRACT: The photocurrent of CdS and CdSe single-crystal photoconductive cells with linear In-Ga contacts is analyzed. The CdS cells were tested with dc and with ac (f = linear In-Ga contacts is analyzed. The CdS cells were tested with dc and with ac (f = linear In-Ga contacts is analyzed. The CdS cells were tested with dc and with ac (f = linear In-Ga contacts is analyzed. The CdS cells were tested with dc and with ac (f = linear In-Ga contacts is analyzed. The CdS cells were tested with dc and with ac (f = linear In-Ga contacts is analyzed. The consider transient conditions. The space charge plays an important role in the nonlinear behavior of the photocurrent. The load of photoresistance may distort considerably its transient characteristics, partially on account of the feedback. This is an important consideration in the design and calcula- account of the feedback. This is an important consideration networks. Formulas that tion of hardware used in correction circuits and compensation networks. Formulas that tion of hardware used in correction circuits and compensation networks. Formulas that the developed of the computation of the transient characteristics of photoresistances are adequate for the computation of the transient characteristics of photoresistances are adequate for the computation of the transient characteristics of photoresistances are adequate for the computation of the transient characteristics of photoresistances are adequate for the computation of the transient characteristics of photoresistances are adequate for the computation of the transient characteristics of photoresistances	
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UR/0000/66/000/000/0005/0032 ACC NR. AT6034348 BOURCE CODE: Svechnikov, S. V. AUTHOR: 134 none ORG: design trend in semi-TITLE: Functional photoelectric converters conductor electronics SOURCE: AN UkrSSR. Poluprovodnikovays, tekhnika i mikroelektronika (Semiconductor engineering and microelectronics). Kiev, Naukova dumka, 1966, 5-32 TOPIC TAGS: photoeffect, photoelectric effect, photodiode, optic element ABSTRACT: The general category of optoelectronic devices, which includes any type of optical-electronic or optical-optical energy converter, is reviewed. Characteristics of commonly used phosphors and luminophors are tabulated, as are specifications for several types of injection diode. The basic complementary combination of an electroluminescent element and a photosensitive two-pole, defined as an optron, is discussed in several forms, and its application to logic circutry is proposed. Fig. 1 shows two schematic forms of the optron. Some functional circuits based on optrons are described, including AND and OR gates, a Card 1/2

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L 08417-67 ACC NR: AT6034348	•	6
Luminescent Elya Elya Fn	<b>,</b>	
Photoelement	,	
Fig. 1. Elementary optron		
a = Uy = const, light in = var; b = Uy = var, light in = 0.		
commutator, half-adder, shift register, and ring counter, M commutator, half-adder, shift register, and ring counter, M ences to the cited circuits are from U.S. sources of several ences to the cited circuits are from U.S. sources of several ences to the concludes that because of their small size and rethe order of nanoseconds, optrons have many potential microst the order of nanoseconds, optrons have many potential microst the order of nanoseconds, optrons have many potential microst the order of nanoseconds, optrons have many potential microst the order of nanoseconds, optrons have many potential microst the order of nanoseconds, optrons have many potential microst the order of nanoseconds.	lectr	onic
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Card 2/2 19	·	

RAKOV, A.N. (Leningrad); SVECHNIKOV, V.A., professor, direktor; ZHDANOV, D.A., chlen-korrespondent akademii meditsinskikh nauk SSSR, direktor.

Arteriosclerosis of the pulmonary artery. Arkh.pat. 15 no.4:84-85 J1-Ag '53. (MLRA 6:11)

1. Gospital'naya terapevticheskaya klimika Leningradskogo sanitarno-gigiyenicheskogo meditsinskogo instituta (for Svechnikov and Bakov). 2. Leningradskiy sanitarno-gigiyenicheskiy meditsinskiy institut (for Zhdanov). 3. Akademiya meditsinskikh nauk SSSR (for Zhdanov). (Arteriosclerosis) (Pulmonary artery)

USSR / Human and Animal Physiology. Blood Circulation.

Abs Jour: Ref Zhur-Biol., No 9, 1958, 41341.

: Svechnikov, V. A.; Ilinskaya, O. B.; Petrova, A. P. : Leningrad Sanitary-Hygiene Medical Institute. Inst : Experimental Reflex Therapy of Hypertension. Title

Orig Pub: Tr. Leningr. san-gigiyen. med. in-ta, 1957, 34,

149-156.

Abstract: No Abstract.

Card 1/1

18.9200 1418 1454 1521

29178 \$/021/61/000/010/005/008 D251/D303

AUTHORS:

Sytechnikov, V.M., Academician AS UkrSSR, and

Pan, V.M.

TITLE:

Phase diagram of the system Cr-Ni-Nb

PERIODICAL: Akademiya nauk Ukrayins'koyi RSR. Dopovidi, no. 10,

1961, 1292 - 1295

TEXT: By constructing a complete diagram of the phase-equilibrium of the system Cr-Ni-Nb with the quadrangle Cr-Ni-Ni3Nb-NbCr2, it bounded by the Cr-Ni-Ni3Nb-NbCr2 quadrangle there is only one quasibinary section NbCr2-Ni3Nb. In the case of a nickel content of over 5 - 7 % it was found that the phase of solid solution in the lowtemperature modification of NbCr, vanished and was replaced by the

Card 1/2

Phase diagram of the system Cr-Ni-Nb

\$/021/61/000/010/005/008 D251/D303

phase of solid solution in the high-temperature modification of NbCr2. The authors claim that this is the first time that the phase diagram of Cr-Ni-Nb has been demonstrated. The investigation was

carried out by the methods of thermal differential tempered-micro-structural, tempered-x-ray-structural and durometric analysis. There are 3 figures and 6 references: 5 Soviet-bloc and 1 non-Soviet-bloc. The reference to the English-language publication reads as follows:: 0. Kubaschewski, A. Schneider, Journ. Inst. Metals, 75, 403, 1948-1949.

ASSOCIATION: Instytut metalofizyky AN URSR (Institute of Metal Phy-

sics AS UkrSSR)

SUBMITTED: May 3, 1961

Card 2/2

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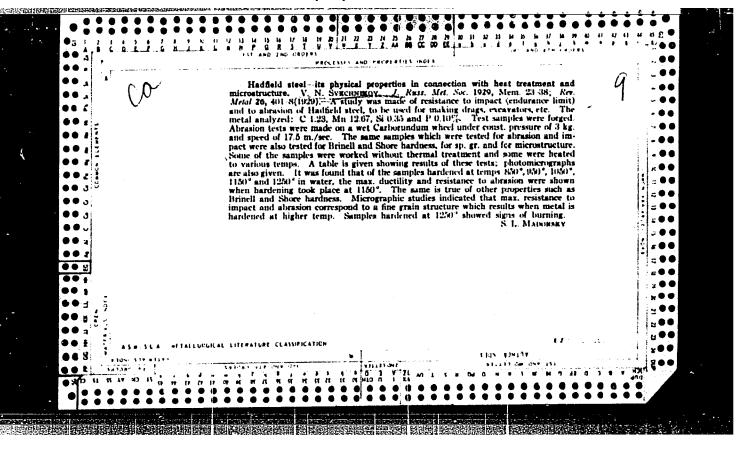
SVECHNIMOV V.M.

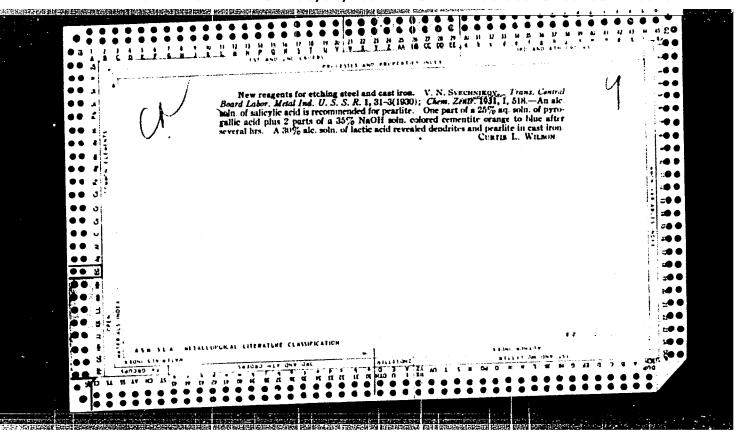
Metals of the future. Nauka i shyttia 11 no.12:7-8 D:61.

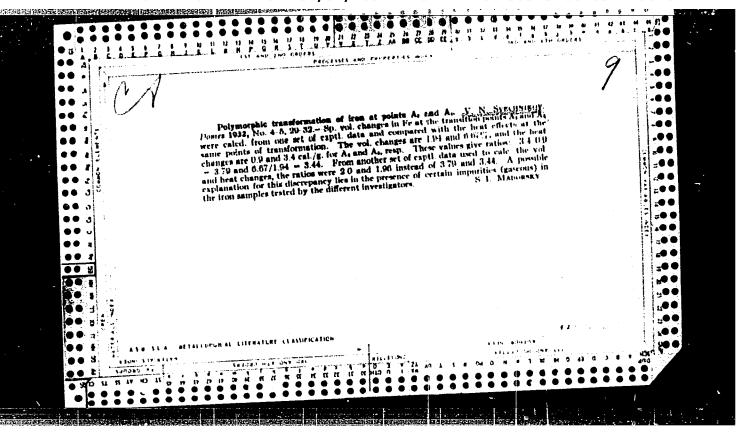
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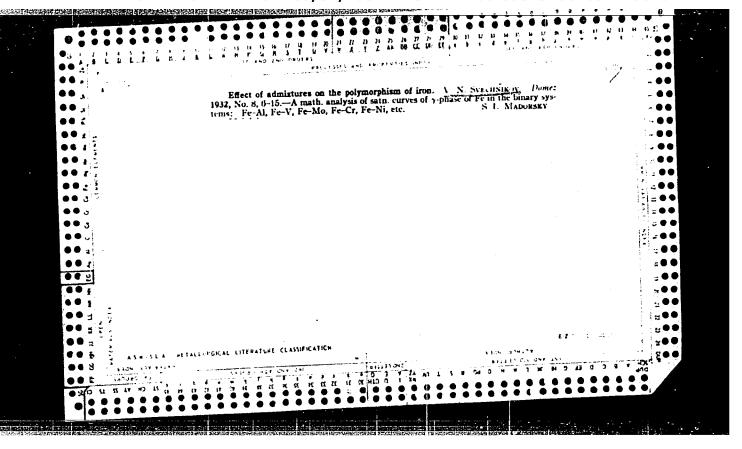
1. AN USSR.

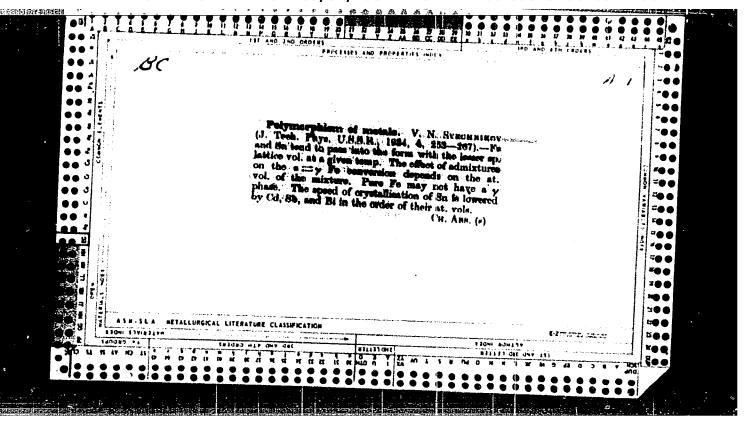
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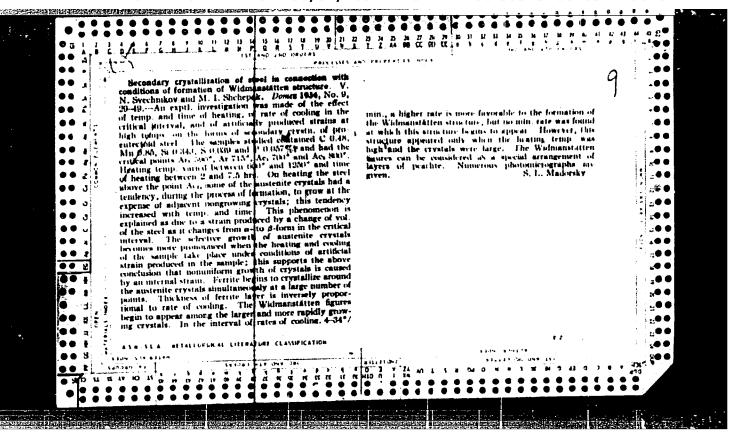


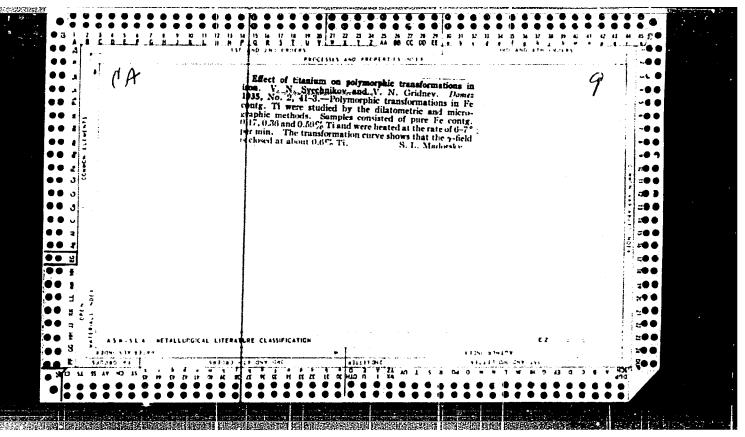




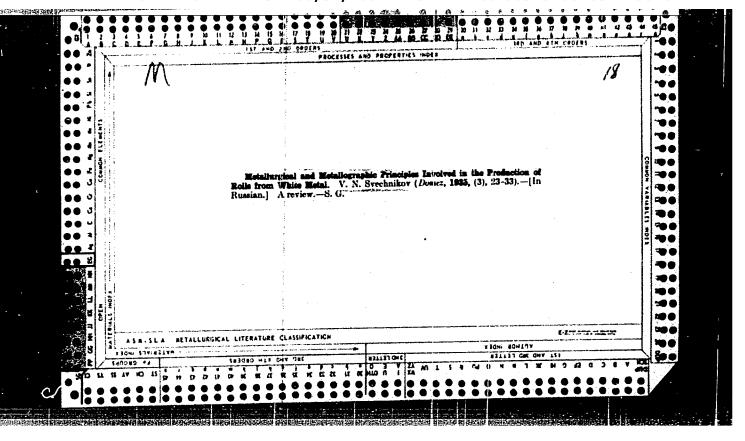


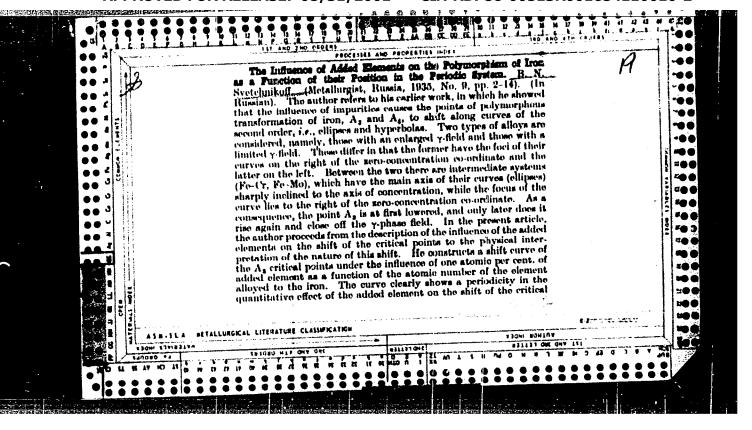


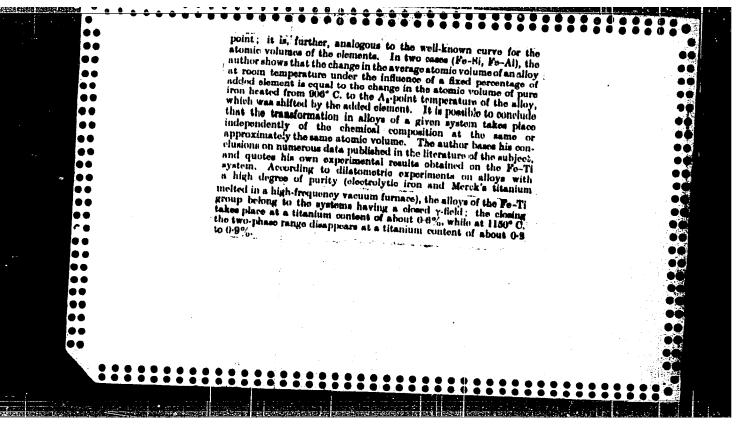


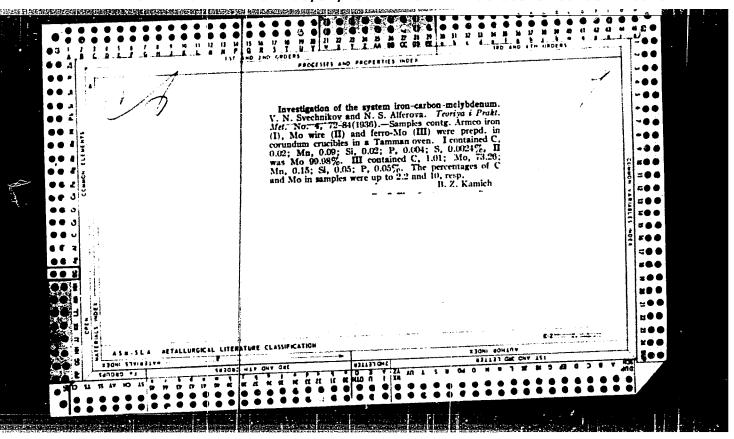


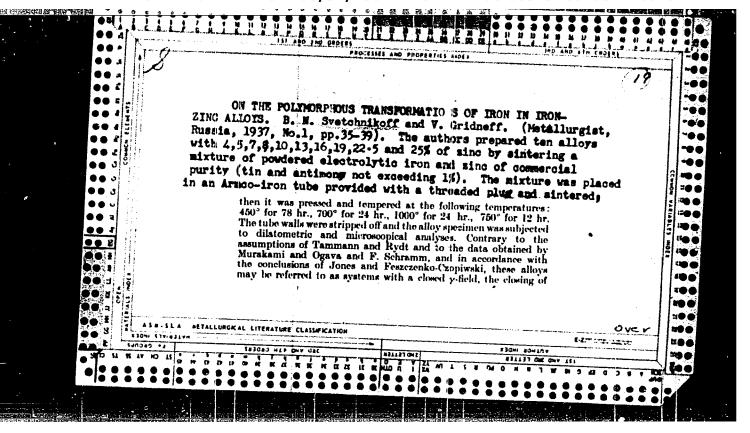
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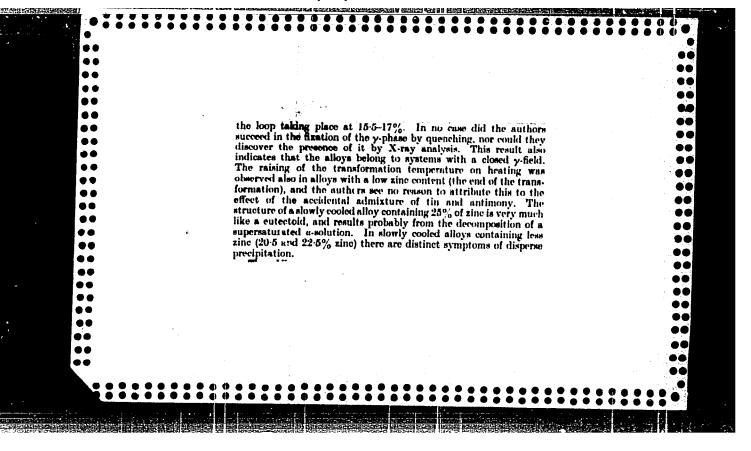




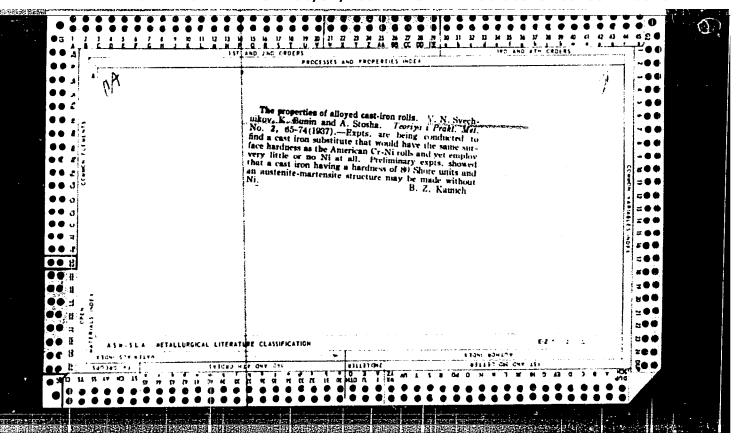


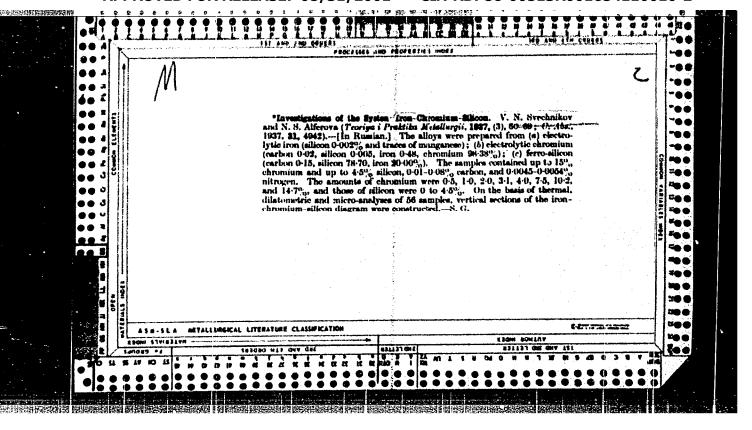


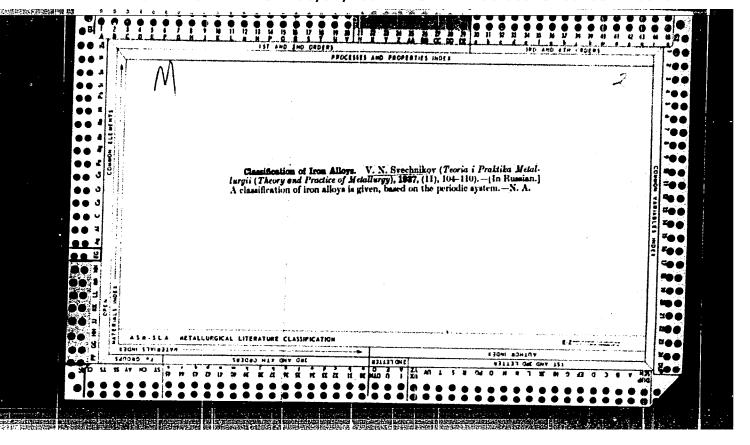


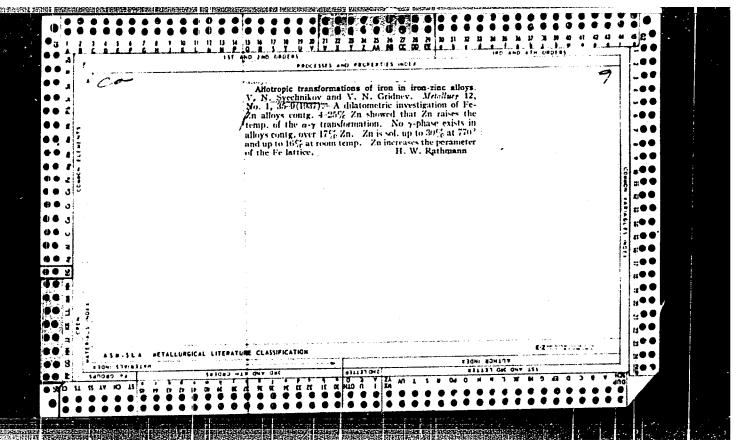


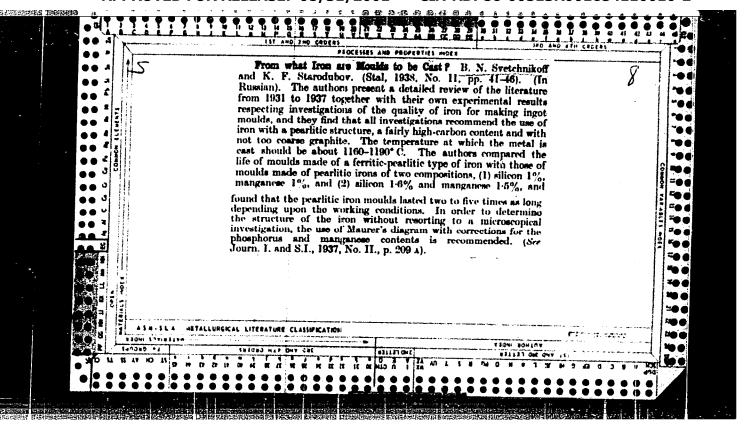
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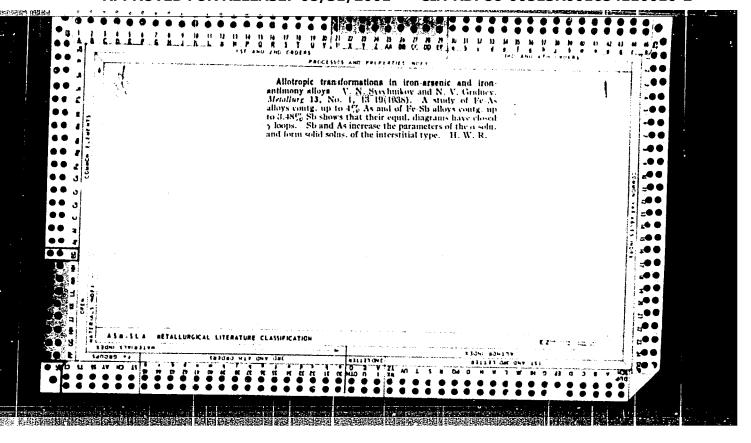


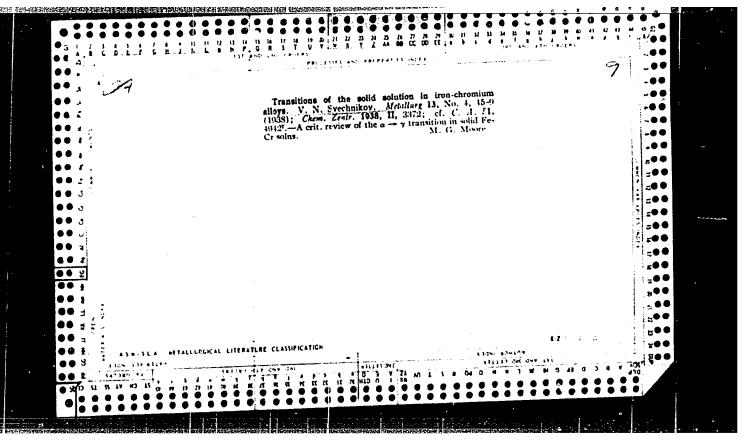


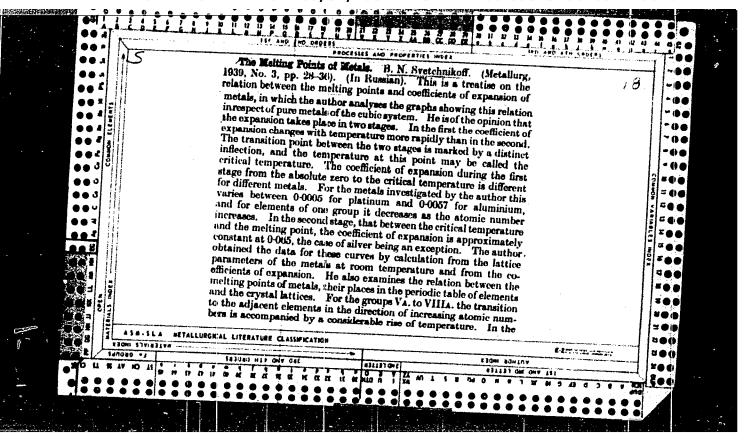




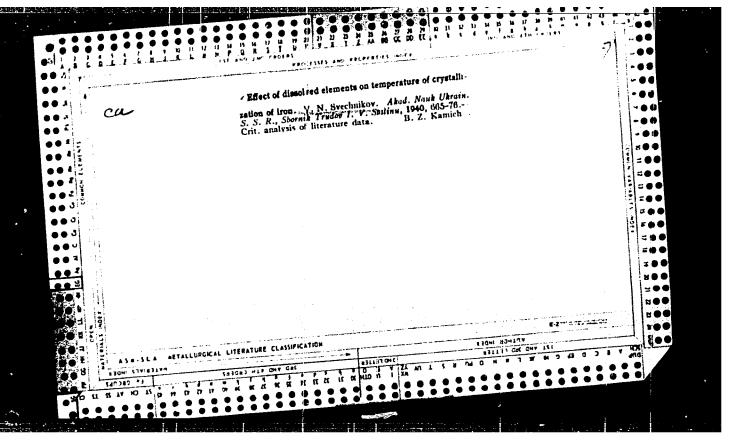


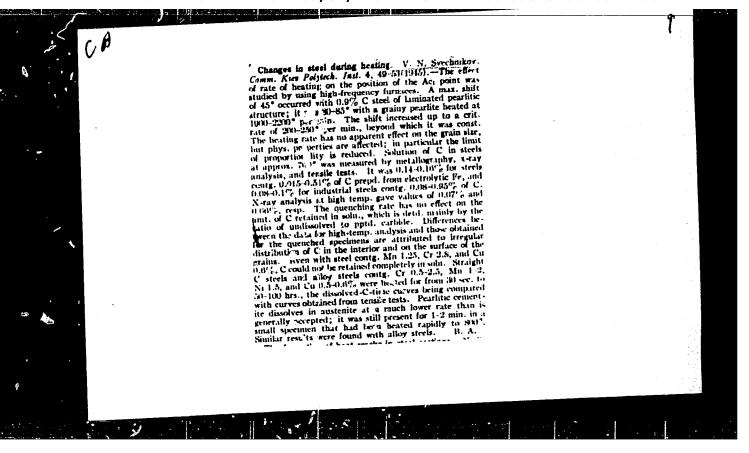


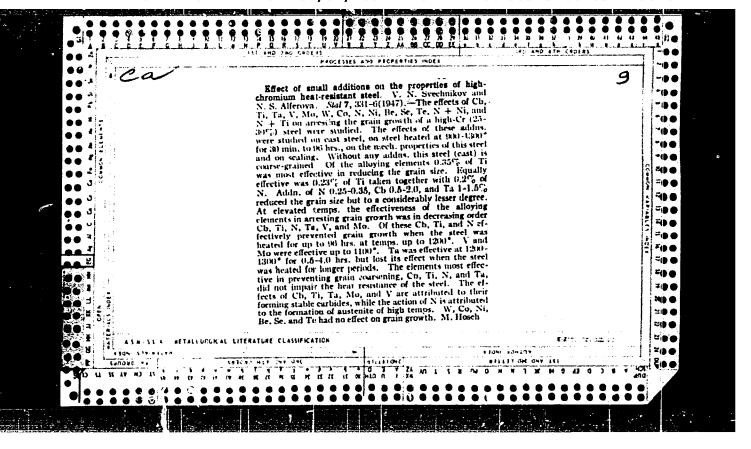


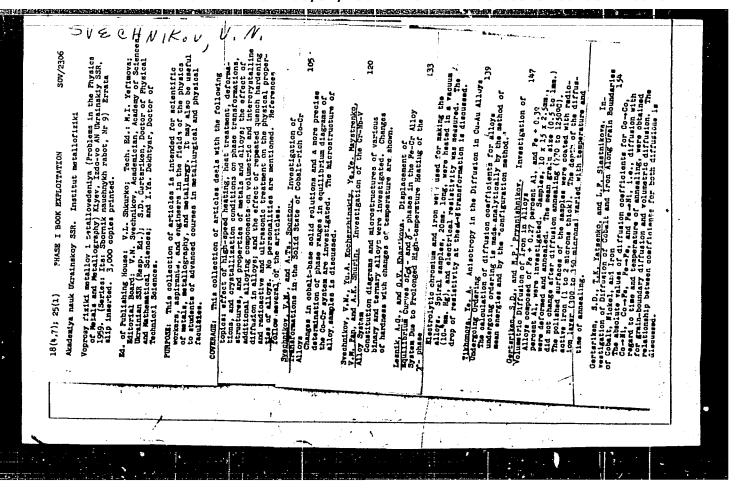


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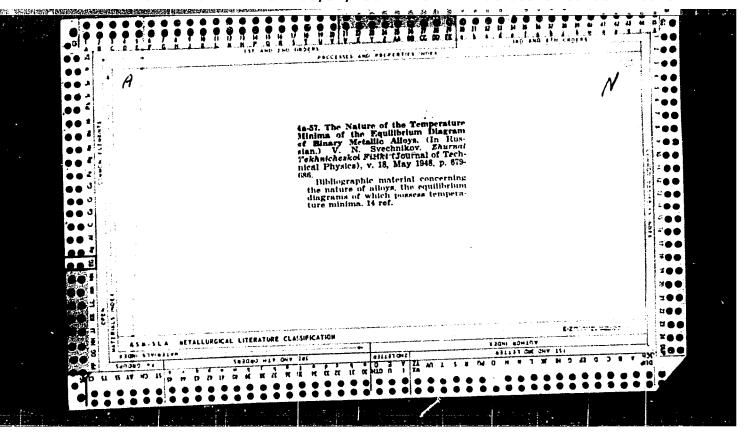






35310. SVECINIKOV, V.N. O Bessemerovskoy Stali. V SB:50 Let Kievsk.
Politekhn. In-Ta. Kiev, 1948, S. 1-32. -Bibliogr: 20 Nezv.

SO: Letopis' Zhurnal'nykh Statey, Vol. 34, Moskva, 1949



SVECHNIKOV, V.H.; ALFEROVA, H.S., kandidat tekhnicheskikh nauk; SOTFER, R.L.

[Interior.]

Quality and periodic structure in centrifugal cast steel pipes.

Trudy Inst. Chern. met. AN URSR 3:62-76 149. (MIRA 8:7)

1. Deystvitel'nyy chlen Akademii nauk USSR. (for Svechnikov)

(Pipe, Steel) (Steel casting—Testing)

GROZIN, B.D.; SYKCHNIKOV, V.M., redaktor; GRIDNEV, V.M., professor, doktor teichnicheskikh nauk, retsenzent; PRITSKER, G.S., tekknicheskiy redaktor

[Mechanical properties of tempered steel] Mekhanicheskie svoistva zakalennoi stali. Kiev, Gos. nauchno-tekhn. izd-vo mashino-stroitel'noi lit-ry, 1951. 166 p. [Microfilm] (MIRA 9:3)

1. Chlen-korrespondent AN USSR (for Grozin) 2. Deystvitel'nyy chlen AN USSR (for Svechnikov)

(Steel--Testing)

deodesy; principles of instruments, equipment and methods of surveying 2. izd. Beograd, Izd. Glavne geodetske uprave, 1951. 210 p. (55-43175) 3301.39

